

FORM PTO 1449 (modified)

ATTY DOCKET NO.: 50169/110

SERIAL NO.: ~~To be assigned~~U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

APPLICANT: Wallace T.-Y. TANG

LIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

FILING DATE: August 14, 1998

GROUP: ~~To be assigned~~  
1763

Date Submitted to PTO: August 14, 1998

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TD	3,986,777	10/76	Roll			
	4,929,828	05/90	Claypool			
	5,081,796	01/92	SCHULTZ			
	5,081,421	01/92	MILLER et al.			
	5,069,002	12/91	SANDHU et al.			
	5,036,015	06/91	SANDHU et al.			
	4,879,258	11/89	FISHER			
	4,793,895	12/88	KAANTA et al.			
	4,569,717	02/86	OHGAMI et al.			
	4,436,367	03/84	LEWIS et al.			
	4,398,791	08/83	DORSEY			
	5,120,966	06/92	KONDO			
	4,718,140	12/87	TIEN			
	4,529,986	07/85	d'AURIA et al.			
	3,510,667	05/70	CLEVELAND et al.			
	4,999,509	03/91	WADA et al.			
	2,578,859	12/51	Teeple et al.			
	4,711,516	12/87	Graber			
	4,776,695	10/88	van Pham et al.			
	4,851,311	07/89	Millis et al.			

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
59-57215(A)	04/84	Japan			Abstract

EXAMINER

DATE CONSIDERED

5/16/00

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication applicant.

WP51\DOCS\IDS\1449.1\8/14/98\5133B\GEQ:km



FORM PTO 1449 (modified)

ATTY DOCKET NO.: 50169/110

SERIAL NO.: ~~To be assigned~~U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

APPLICANT: Wallace T.-Y. TANG

09/134147

LIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

FILING DATE: August 14, 1998

GROUP: ~~To be assigned~~

1763

Date Submitted to PTO: August 14, 1998

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		3,623,813	11/71	HAEMAN			
		4,618,262	10/86	MAYDAN et al.			
		5,046,849	09/91	SEVERIN et al.			
		4,998,021	03/91	MIMASAKA			
		2,973,686	03/61	DREYFUS et al.			
		3,630,795	12/71	Vorie			
		5,433,651	07/95	Lustig et al.			
		5,483,568	01/96	Yano et al.			
		5,308,447	05/94	Lewis et al.			
		5,499,733	03/96	Litvak			
		3,869,211	03/75	Watanabe et al.			
		4,680,084	07/87	Heimann et al.			
		4,672,200	06/87	Claypool et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

--	--	--	--	--	--	--	--

EXAMINER

DATE CONSIDERED

5/6/00

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SERIAL NO. 08/134,147

APPLICANT: Wallace T.Y. TANG

FILING DATE: August 14, 1998

GROUP: ~~1765~~  
176.3

Date Submitted to PTO: March 17, 1999

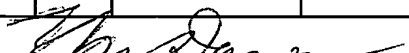
## U.S. PATENT DOCUMENTS

[illegible]

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

JD		A. Novembre	✓	BACUS - 9th Annual Symposium, "Automated Process Control of Poly(Butene-1-Sulfone)
		et al.		PBS Resist Development," (September 1989) pp. 139-144
JD		A. Novembre		SPIE, Vol. 1087, Integrated Circuit Metrology, Inspection, and Process Control III (1989)
		et al.	✓	"An In Situ Interferometric Analysis of Resist Development on Photomask Substrates, pp. 460-468
JD		A. Novembre		SPIE, Vol. 1809, 12th Annual BACUS Symposium (1992), "Initial manufacturing performance of an actively
		et al.	✓	controlled PBS resist development process (pp. 76-84
EXAMINER				DATE CONSIDERED <span style="margin-left: 50px;">5/6/00</span>

*\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.*